



IFW

THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Application of:

Jhon-Jhy Liaw

Group Art Unit: 2811

Serial No.: 10/797,945

Examiner: Vu, Quang D.

Filed: March 10, 2004

In Response to Office Action

Dated: Feb. 25, 2005

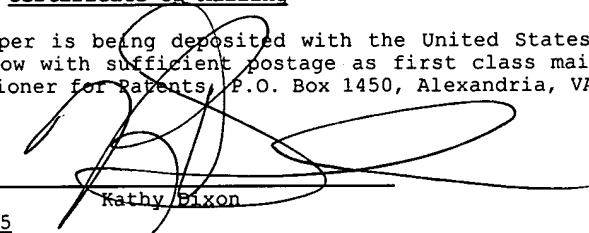
For: Contact Structure for Nanometer Characteristic Dimensions

Attorney Docket No.: 67,200-1253 (2003-1046)

Certificate of Mailing

I hereby certify that this paper is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Date: Mar. 24, 2005

  
Kathy Dixon

RESPONSE TO OFFICE ACTION

Commissioner for Patents  
Alexandria, VA 22313-1450

Dear Sir:

In response to an Office Action mailed Feb. 25, 2005 of a restriction requirement imposed by the Examiner, the Applicants hereby elect with traverse the prosecution of Groups II, claims 18-37. The Applicants respectfully request the Examiner to consider the following remarks.